

Notice of References Cited	Application/Control No. 10/666,868		Applicant(s)/Patent Under Reexamination KEAY ET AL.	
	Examiner GEORGE PARK		Art Unit 3623	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-7,020,621 B1	03-2006	Feria et al.	705/10
*	B	US-2003/0187707 A1	10-2003	Hack et al.	705/7
*	C	US-2002/0042751 A1	04-2002	Sarno, Anthony	705/26
*	D	US-7,165,036 B2	01-2007	Kruk et al.	705/1
*	E	US-2001/0053991 A1	12-2001	Bonabeau, Eric W.	705/7
*	F	US-2004/0148209 A1	07-2004	Church et al.	705/007
*	G	US-2004/0162763 A1	08-2004	Hoskin et al.	705/026
*	H	US-7,076,474 B2	07-2006	Jin et al.	706/45
*	I	US-2003/0120528 A1	06-2003	Kruk et al.	705/7
*	J	US-2003/0144953 A1	07-2003	Razum et al.	705/40
*	K	US-2004/0039619 A1	02-2004	Zarb, Joseph J.	705/7
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.